CMOS Digital Integrated Circuits Silicon Monolithic

## **74VHC573FT**

#### 1. Functional Description

· Octal D-Type Latch with 3-State Outputs

#### 2. General

The 74VHC573FT is an advanced high speed CMOS OCTAL LATCH with 3-STATE OUTPUT fabricated with silicon gate C2MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

This 8-bit D-type latch is controlled by a latch enable input (LE) and an output enable input ( $\overline{\text{OE}}$ ).

When the  $\overline{OE}$  input is high, the eight outputs are in a high impedance state.

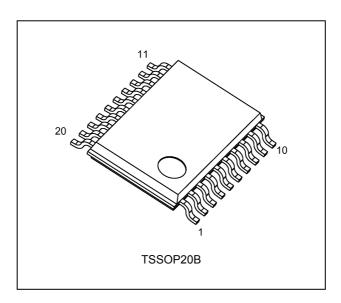
An input protection circuit ensures that 0 to 5.5 V can be applied to the input pins without regard to the supply voltage. This device can be used to interface 5 V to 3 V systems and two supply systems such as battery back up. This circuit prevents device destruction due to mismatched supply and input voltages.

#### 3. Features

- (1) AEC-Q100 (Rev. H) (Note 1)
- (2) Wide operating temperature range:  $T_{opr} = -40$  to 125 °C
- (3) High speed:  $t_{pd} = 4.5$  ns (typ.) at  $V_{CC} = 5.0$  V
- (4) Low power dissipation:  $I_{CC} = 4.0 \mu A \text{ (max)}$  at  $T_a = 25^{\circ}\text{C}$
- (5) High noise immunity:  $V_{NIH} = V_{NIL} = 28\% V_{CC}$  (min)
- (6) Power-down protection is provided on all inputs.
- (7) Balanced propagation delays:  $t_{PLH} \approx t_{PHL}$
- (8) Wide operating voltage range:  $V_{CC(opr)} = 2.0 \text{ V}$  to 5.5 V
- (9) Low noise:  $V_{OLP} = 1.0 \text{ V (max)}$
- (10) Pin and function compatible with the 74 series (74AC/HC/AHC/LV etc.) 573 type.

Note 1: This device is compliant with the reliability requirements of AEC-Q100. For details, contact your Toshiba sales representative.

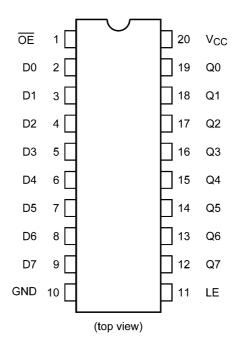
#### 4. Packaging



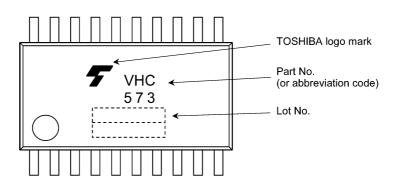
Start of commercial production



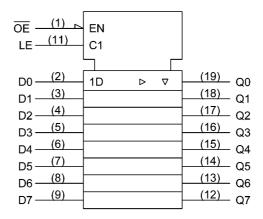
### 5. Pin Assignment



## 6. Marking



### 7. IEC Logic Symbol



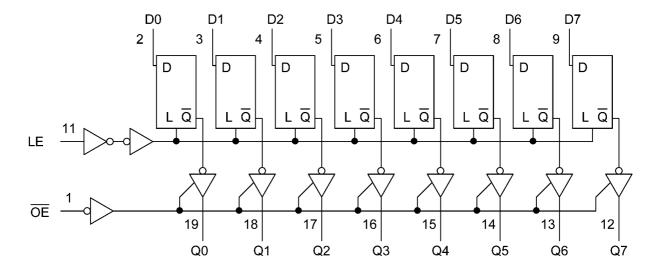
#### 8. Truth Table

INPUT OE	INPUT LE	INPUT D	OUTPUT
Н	Х	Х	Z
L	L	Х	Qn
L	Н	L	L
L	Н	Н	Н

X: Don't careZ: High impedance

Qn: Q outputs are latched at the time when the LE input is taken to low logic level.

## 9. System Diagram





#### 10. Absolute Maximum Ratings (Note)

Characteristics	Symbol	Note	Rating	Unit
Supply voltage	V <sub>CC</sub>		-0.5 to 7.0	V
Input voltage	V <sub>IN</sub>		-0.5 to 7.0	V
Output voltage	V <sub>OUT</sub>		-0.5 to V <sub>CC</sub> + 0.5	V
Input diode current	I <sub>IK</sub>		-20	mA
Output diode current	I <sub>OK</sub>		±20	mA
Output current	I <sub>OUT</sub>		±25	mA
V <sub>CC</sub> /ground current	I <sub>CC</sub>		±75	mA
Power dissipation	P <sub>D</sub>	(Note 1)	180	mW
Storage temperature	T <sub>stg</sub>		-65 to 150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 1: 180 mW in the range of  $T_a$  = -40 to 85 °C. From  $T_a$  = 85 to 125 °C a derating factor of -3.25 mW/°C shall be applied until 50 mW.

#### 11. Operating Ranges (Note)

Characteristics	Symbol	Test Condition	Rating	Unit
Supply voltage	V <sub>CC</sub>		2.0 to 5.5	V
Input voltage	V <sub>IN</sub>		0 to 5.5	V
Output voltage	V <sub>OUT</sub>		0 to V <sub>CC</sub>	V
Operating temperature	T <sub>opr</sub>		-40 to 125	°C
Input rise and fall times	dt/dv	$V_{CC}$ = 3.3 ± 0.3 V	0 to 100	ns/V
		$V_{CC}$ = 5.0 ± 0.5 V	0 to 20	

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs and bus inputs must be tied to either  $V_{CC}$  or GND.



### 12. Electrical Characteristics

## 12.1. DC Characteristics (Unless otherwise specified, $T_a$ = 25 °C)

Characteristics	Symbol	Test Condition	Test Condition		Min	Тур.	Max	Unit
High-level input voltage	V <sub>IH</sub>	_		2.0	1.50	_	_	V
				3.0 to 5.5	V <sub>CC</sub> × 0.7	_	_	
Low-level input voltage	V <sub>IL</sub>	_		2.0	_	_	0.50	V
				3.0 to 5.5	_	_	$V_{CC} \times 0.3$	
High-level output voltage	V <sub>OH</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $I_{OH} = -50  \mu\text{A}$		2.0	1.9	2.0	_	V
				3.0	2.9	3.0	_	
				4.5	4.4	4.5	_	
			I <sub>OH</sub> = -4 mA	3.0	2.58	_	_	
			I <sub>OH</sub> = -8 mA	4.5	3.94	_	_	
Low-level output voltage	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 50 μA	2.0	_	0.0	0.1	V
				3.0	_	0.0	0.1	
				4.5	_	0.0	0.1	
			I <sub>OL</sub> = 4 mA	3.0	_	_	0.36	
			I <sub>OL</sub> = 8 mA	4.5	_	_	0.36	
3-state output OFF-state leakage current	I <sub>OZ</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or GND}$		5.5	_	_	±0.25	μА
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = 5.5 V or GND		0 to 5.5	_	_	±0.1	
Quiescent supply current	Icc	V <sub>IN</sub> = V <sub>CC</sub> or GND		5.5	_		4.0	

## 12.2. DC Characteristics (Unless otherwise specified, T<sub>a</sub> = -40 to 85 °C)

Characteristics	Symbol	Test Condition		V <sub>CC</sub> (V)	Min	Max	Unit
High-level input voltage	V <sub>IH</sub>	_		2.0	1.50	_	V
				3.0 to 5.5	$V_{CC} \times 0.7$	_	
Low-level input voltage	V <sub>IL</sub>	_		2.0	_	0.50	V
				3.0 to 5.5	_	$V_{CC} \times 0.3$	
High-level output voltage	V <sub>OH</sub>	$V_{IN} = V_{IH}$ or $V_{IL}$	I <sub>OH</sub> = -50 μA	2.0	1.9	_	V
				3.0	2.9	_	
				4.5	4.4	_	
			I <sub>OH</sub> = -4 mA	3.0	2.48	_	
			I <sub>OH</sub> = -8 mA	4.5	3.80	_	
Low-level output voltage	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 50 μA	2.0	_	0.1	V
				3.0	_	0.1	
				4.5	_	0.1	
			I <sub>OL</sub> = 4 mA	3.0	_	0.44	
			I <sub>OL</sub> = 8 mA	4.5	_	0.44	
3-state output OFF-state leakage current	I <sub>OZ</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or GND}$		5.5	_	±2.50	μА
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = 5.5 V or GND	-	0 to 5.5	_	±1.0	
Quiescent supply current	I <sub>CC</sub>	$V_{IN} = V_{CC}$ or GND		5.5	_	40.0	



## 12.3. DC Characteristics (Unless otherwise specified, $T_a$ = -40 to 125 °C)

Characteristics	Symbol	Test Condition	on	V <sub>CC</sub> (V)	Min	Max	Unit
High-level input voltage	V <sub>IH</sub>	_		2.0	1.50	_	V
				3.0 to 5.5	$V_{CC} \times 0.7$	_	
Low-level input voltage	V <sub>IL</sub>	_		2.0	_	0.50	٧
				3.0 to 5.5		$V_{CC} \times 0.3$	
High-level output voltage	V <sub>OH</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OH</sub> = -50 μA	2.0	1.9	_	٧
				3.0	2.9	_	
				4.5	4.4	_	
			$I_{OH} = -4 \text{ mA}$	3.0	2.40	_	
			$I_{OH}$ = -8 mA	4.5	3.70	_	
Low-level output voltage	V <sub>OL</sub>	V <sub>IN</sub> = V <sub>IH</sub> or V <sub>IL</sub>	I <sub>OL</sub> = 50 μA	2.0		0.1	٧
				3.0	_	0.1	
				4.5	_	0.1	
			$I_{OL} = 4 \text{ mA}$	3.0	_	0.55	
			$I_{OL}$ = 8 mA	4.5	_	0.55	
3-state output OFF-state leakage current	I <sub>OZ</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$ $V_{OUT} = V_{CC} \text{ or GND}$		5.5	_	±10.0	μА
Input leakage current	I <sub>IN</sub>	V <sub>IN</sub> = 5.5 V or GND		0 to 5.5		±2.0	μА
Quiescent supply current	Icc	V <sub>IN</sub> = V <sub>CC</sub> or GND		5.5		80.0	μΑ



## 12.4. Timing Requirements (Unless otherwise specified, $T_a = 25$ °C, Input: $t_f = t_f = 3$ ns)

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Limit	Unit
Minimum pulse width	t <sub>w(H)</sub>	_	$3.3 \pm 0.3$	5.0	ns
(LE)			$5.0\pm0.5$	5.0	ns
Minimum setup time	t <sub>S</sub>	_	$3.3 \pm 0.3$	3.5	ns
			$5.0 \pm 0.5$	3.5	ns
Minimum hold time	t <sub>h</sub>	_	$3.3 \pm 0.3$	1.5	ns
			$5.0 \pm 0.5$	1.5	ns

# 12.5. Timing Requirements (Unless otherwise specified, $T_a$ = -40 to 85°C, Input: $t_f$ = $t_f$ = 3 ns)

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Limit	Unit
Minimum pulse width	t <sub>w(H)</sub>	_	$3.3 \pm 0.3$	5.0	ns
(LE)			$5.0 \pm 0.5$	5.0	
Minimum setup time	t <sub>S</sub>	_	$3.3 \pm 0.3$	3.5	ns
			$5.0 \pm 0.5$	3.5	
Minimum hold time	t <sub>h</sub>	_	$3.3 \pm 0.3$	1.5	ns
			$5.0 \pm 0.5$	1.5	

# 12.6. Timing Requirements (Unless otherwise specified, $T_a$ = -40 to 125 °C, Input: $t_r$ = $t_f$ = 3 ns)

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Limit	Unit
Minimum pulse width	t <sub>w(H)</sub>	_	$3.3 \pm 0.3$	5.0	ns
(LE)			$5.0 \pm 0.5$	5.0	
Minimum setup time	t <sub>S</sub>	_	$3.3 \pm 0.3$	4.5	ns
			$5.0 \pm 0.5$	4.0	
Minimum hold time	t <sub>h</sub>	_	$3.3 \pm 0.3$	1.5	ns
			$5.0 \pm 0.5$	1.5	



### 12.7. AC Characteristics (Unless otherwise specified, $T_a = 25$ °C, Input: $t_r = t_f = 3$ ns)

Characteristics	Symbol	Note	Test Condition	V <sub>CC</sub> (V)	C <sub>L</sub> (pF)	Min	Тур.	Max	Unit
Propagation delay time	t <sub>PLH</sub> ,t <sub>PHL</sub>		_	$3.3 \pm 0.3$	15	_	7.6	11.9	ns
(LE-Q)					50	_	10.1	15.4	
				5.0 ± 0.5	15	_	5.0	7.7	
					50	_	6.5	9.7	
Propagation delay time	t <sub>PLH</sub> ,t <sub>PHL</sub>		_	$3.3 \pm 0.3$	15	_	7.0	11.0	ns
(D-Q)					50	_	9.5	14.5	
				5.0 ± 0.5	15	_	4.5	6.8	
					50	_	6.0	8.8	
3-state output enable time	$t_{PZL},t_{PZH}$		$R_L = 1 k\Omega$	$3.3 \pm 0.3$	15	_	7.3	11.5	ns
					50	_	9.8	15.0	
				5.0 ± 0.5	15	_	5.2	7.7	
					50	_	6.7	9.7	
3-state output disable time	$t_{PLZ}, t_{PHZ}$		$R_L = 1 k\Omega$	$3.3 \pm 0.3$	50	_	10.7	14.5	ns
				5.0 ± 0.5	50	_	6.7	9.7	
Output skew	t <sub>osLH</sub> ,t <sub>osHL</sub>	(Note 1)	_	$3.3\pm0.3$	50	_	_	1.5	ns
				5.0 ± 0.5	50	_	_	1.0	
Input capacitance	C <sub>IN</sub>		_			_	4	10	pF
Output capacitance	C <sub>OUT</sub>		_			_	6	_	pF
Power dissipation capacitance	C <sub>PD</sub>	(Note 2)		•		_	29	_	pF

Note 1: Parameter guaranteed by design.  $(t_{osLH} = |t_{PLH}m-t_{PLH}n|, t_{osHL} = |t_{PHL}m-t_{PHL}n|)$ 

Note 2: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load. Average operating current can be obtained by the equation.

 $I_{CC(opr)} = C_{PD} \times V_{CC} \times f_{IN} + I_{CC}/8$  (per latch)

And the total  $C_{\text{PD}}$  when n pcs. of latch operate can be gained by the following equation.

 $C_{PD}$  (total) = 21 + 8 × n

## 12.8. AC Characteristics (Unless otherwise specified, $T_a$ = -40 to 85 °C, Input: $t_r$ = $t_f$ = 3 ns)

Characteristics	Symbol	Note	Test Condition	V <sub>CC</sub> (V)	C <sub>L</sub> (pF)	Min	Max	Unit
Propagation delay time	t <sub>PLH</sub> ,t <sub>PHL</sub>		_	$3.3 \pm 0.3$	15	1.0	14.0	ns
(LE-Q)					50	1.0	17.5	
				$5.0 \pm 0.5$	15	1.0	9.0	
					50	1.0	11.0	
Propagation delay time	t <sub>PLH</sub> ,t <sub>PHL</sub>		_	$3.3 \pm 0.3$	15	1.0	13.0	ns
(D-Q)					50	1.0	16.5	
				$5.0 \pm 0.5$	15	1.0	8.0	
					50	1.0	10.0	
3-state output enable time	t <sub>PZL</sub> ,t <sub>PZH</sub>		$R_L = 1 k\Omega$	$3.3 \pm 0.3$	15	1.0	13.5	ns
					50	1.0	17.0	
				5.0 ± 0.5	15	1.0	9.0	
					50	1.0	11.0	
3-state output disable time	t <sub>PLZ</sub> ,t <sub>PHZ</sub>		$R_L = 1 k\Omega$	$3.3\pm0.3$	50	1.0	16.5	ns
				5.0 ± 0.5	50	1.0	11.0	
Output skew	t <sub>osLH</sub> ,t <sub>osHL</sub>	(Note 1)	_	$3.3\pm0.3$	50	_	1.5	ns
				5.0 ± 0.5	50	_	1.0	ns
Input capacitance	C <sub>IN</sub>		_			_	10	pF

Note 1: Parameter guaranteed by design. ( $t_{osLH} = |t_{PLH}m - t_{PLH}n|$ ,  $t_{osHL} = |t_{PHL}m - t_{PHL}n|$ )



# 12.9. AC Characteristics (Unless otherwise specified, $T_a$ = -40 to 125 °C, Input: $t_r$ = $t_f$ = 3 ns)

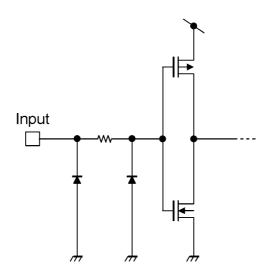
Characteristics	Symbol	Note	Test Condition	V <sub>CC</sub> (V)	C <sub>L</sub> (pF)	Min	Max	Unit
Propagation delay time	t <sub>PLH</sub> ,t <sub>PHL</sub>		_	$3.3 \pm 0.3$	15	1.0	16.0	ns
(LE-Q)					50	1.0	19.5	
				5.0 ± 0.5	15	1.0	10.5	
					50	1.0	12.5	
Propagation delay time	t <sub>PLH</sub> ,t <sub>PHL</sub>		_	$3.3 \pm 0.3$	15	1.0	15.0	ns
(D-Q)					50	1.0	18.5	
				5.0 ± 0.5	15	1.0	9.0	
					50	1.0	11.0	
3-state output enable time	t <sub>PZL</sub> ,t <sub>PZH</sub>		$R_L = 1 k\Omega$	$3.3 \pm 0.3$	15	1.0	15.5	ns
					50	1.0	19.0	
				5.0 ± 0.5	15	1.0	10.5	
					50	1.0	12.5	
3-state output disable time	$t_{PLZ}, t_{PHZ}$		$R_L = 1 k\Omega$	$3.3 \pm 0.3$	50	1.0	18.5	ns
				5.0 ± 0.5	50	1.0	12.5	
Output skew	t <sub>osLH</sub> ,t <sub>osHL</sub>	(Note 1)	_	$3.3 \pm 0.3$	50	1	1.5	ns
				5.0 ± 0.5	50		1.0	
Input capacitance	C <sub>IN</sub>						10	pF

Note 1: Parameter guaranteed by design. ( $t_{osLH} = |t_{PLH}m - t_{PLH}n|$ ,  $t_{osHL} = |t_{PHL}m - t_{PHL}n|$ )

## 12.10. Noise Characteristics (Unless otherwise specified, $T_a$ = 25°C, Input: $t_r$ = $t_f$ = 3 ns)

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Тур.	Limit	Unit
Quiet output maximum dynamic V <sub>OL</sub>	V <sub>OLP</sub>	C <sub>L</sub> = 50 pF	5.0	0.8	1.0	V
Quiet output minimum dynamic V <sub>OL</sub>	V <sub>OLV</sub>	C <sub>L</sub> = 50 pF	5.0	-0.8	-1.0	
Minimum high-level dynamic input voltage	$V_{IHD}$	C <sub>L</sub> = 50 pF	5.0	_	3.5	
Maximum low-level dynamic input voltage	$V_{ILD}$	C <sub>L</sub> = 50 pF	5.0		1.5	

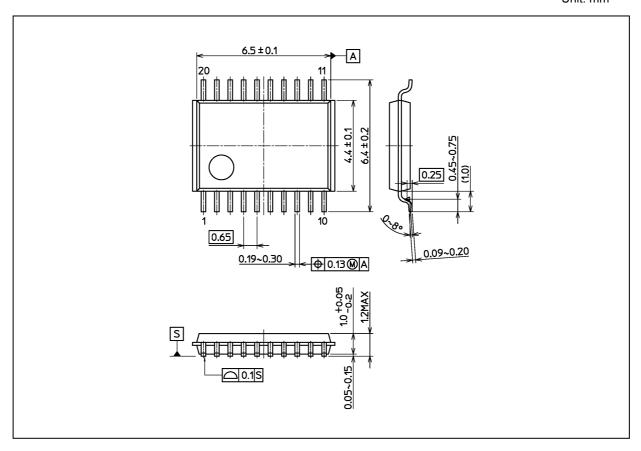
## 13. Input Equivalent Circuit





## **Package Dimensions**

Unit: mm



Weight: 0.071 g (typ.)

	Package Name(s)
Nickname: TSSOP20B	



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